

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination PATTON ET AL.	
		Examiner Brian Q Le	Art Unit 2623	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5,393,976	02-1995	Koike, Hirotami	250/310
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U		Kurihara et al. "Fabrication of Functional Probes for Near-field Optic Microscopy", Lasers and Electro-Optics, 1997 pages: 148-149.
V		
W		
X		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.